

SIPMOS® Power-Transistor

Feature

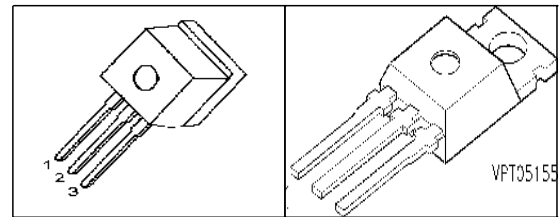
- N-Channel
- Enhancement mode
- 175°C operating temperature
- Avalanche rated
- dv/dt rated
- Pb-free lead plating; RoHS compliant

Product Summary

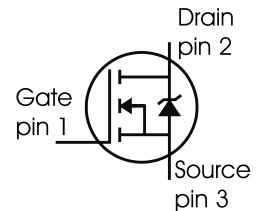
| | | |
|--------------|-----|----|
| V_{DS} | 100 | V |
| $R_{DS(on)}$ | 44 | mΩ |
| I_D | 35 | A |

PG-TO262-3-1

PG-TO220-3-1



| Type | Package | Ordering Code | Marking |
|----------|--------------|---------------|---------|
| SPP35N10 | PG-TO220-3-1 | Q67042-S4123 | 35N10 |
| SPI35N10 | PG-TO262-3-1 | Q67042-S4124 | 35N10 |



Maximum Ratings, at $T_j = 25\text{ °C}$, unless otherwise specified

| Parameter | Symbol | Value | Unit |
|---|--------------------|-------------|-------|
| Continuous drain current | I_D | 35 | A |
| $T_C=25\text{ °C}$ | | 35 | |
| $T_C=100\text{ °C}$ | | 26.4 | |
| Pulsed drain current | $I_D \text{ puls}$ | 140 | |
| $T_C=25\text{ °C}$ | | | |
| Avalanche energy, single pulse | E_{AS} | 245 | mJ |
| $I_D=35\text{ A}$, $V_{DD}=25\text{ V}$, $R_{GS}=25\text{ Ω}$ | | | |
| Reverse diode dv/dt | dv/dt | 6 | kV/μs |
| $I_S=35\text{ A}$, $V_{DS}=80\text{ V}$, $di/dt=200\text{ A/μs}$, $T_{jmax}=175\text{ °C}$ | | | |
| Gate source voltage | V_{GS} | ±20 | V |
| Power dissipation | P_{tot} | 150 | W |
| $T_C=25\text{ °C}$ | | | |
| Operating and storage temperature | T_j, T_{stg} | -55... +175 | °C |
| IEC climatic category; DIN IEC 68-1 | | 55/175/56 | |

Thermal Characteristics

| Parameter | Symbol | Values | | | Unit |
|---|------------|--------|------|----------|------|
| | | min. | typ. | max. | |
| Characteristics | | | | | |
| Thermal resistance, junction - case | R_{thJC} | - | - | 1 | K/W |
| Thermal resistance, junction - ambient, leaded | R_{thJA} | - | - | 62 | |
| SMD version, device on PCB: @ min. footprint @ 6 cm ² cooling area ^{F)} | R_{thJA} | - | - | 62 40 | |

Electrical Characteristics, at $T_j = 25\text{ }^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Values | | | Unit |
|--|---------------|--------|-----------|----------|-----------|
| | | min. | typ. | max. | |
| Static Characteristics | | | | | |
| Drain-source breakdown voltage $V_{GS}=0V, I_D=1mA$ | $V_{(BR)DSS}$ | 100 | - | - | V |
| Gate threshold voltage, $V_{GS} = V_{DS}$ $I_D=83\mu A$ | $V_{GS(th)}$ | 2.1 | 3 | 4 | |
| Zero gate voltage drain current $V_{DS}=100V, V_{GS}=0V, T_j=25^\circ C$ $V_{DS}=100V, V_{GS}=0V, T_j=125^\circ C$ | I_{DSS} | - | 0.01 1 | 1 100 | μA |
| Gate-source leakage current $V_{GS}=20V, V_{DS}=0V$ | I_{GSS} | - | 1 | 100 | |
| Drain-source on-state resistance $V_{GS}=10V, I_D=26.4A$ | $R_{DS(on)}$ | - | 36 | 44 | $m\Omega$ |

¹Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical without blown air.

Electrical Characteristics, at $T_j = 25\text{ }^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Conditions | Values | | | Unit |
|-----------|--------|------------|--------|------|------|------|
| | | | min. | typ. | max. | |

Dynamic Characteristics

| | | | | | | |
|------------------------------|--------------|---|----|------|------|----|
| Transconductance | g_{fs} | $V_{DS} \geq 2 \cdot I_D \cdot R_{DS(on)max}$ $I_D = 26.4\text{A}$ | 12 | 23 | - | S |
| Input capacitance | C_{iss} | $V_{GS} = 0\text{V}$, $V_{DS} = 25\text{V}$, $f = 1\text{MHz}$ | - | 1180 | 1570 | pF |
| Output capacitance | C_{oss} | | - | 245 | 326 | |
| Reverse transfer capacitance | C_{rss} | | - | 137 | 206 | |
| Turn-on delay time | $t_{d(on)}$ | $V_{DD} = 50\text{V}$, $V_{GS} = 10\text{V}$, $I_D = 35\text{A}$, $R_G = 7\Omega$ | - | 12.2 | 18.3 | ns |
| Rise time | t_r | | - | 63 | 95 | |
| Turn-off delay time | $t_{d(off)}$ | | - | 39 | 59 | |
| Fall time | t_f | | - | 23 | 34 | |

Gate Charge Characteristics

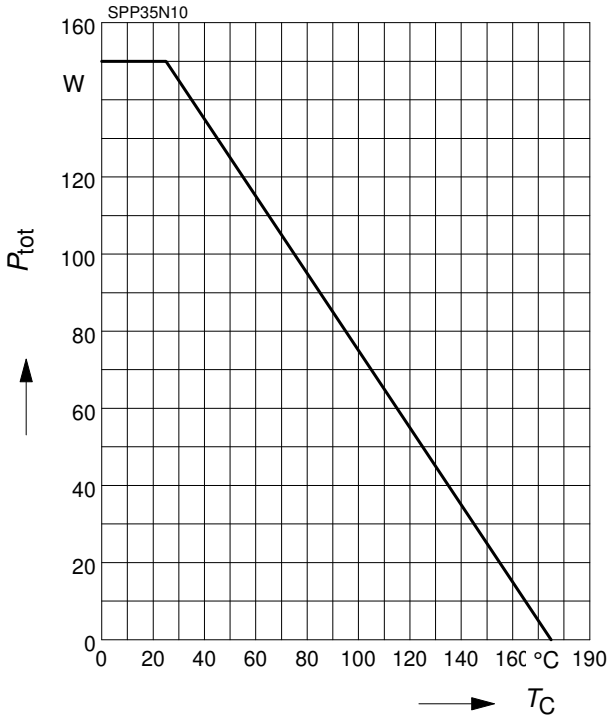
| | | | | | | |
|-----------------------|-----------------|--|---|-----|-----|----|
| Gate to source charge | Q_{gs} | $V_{DD} = 80\text{V}$, $I_D = 35\text{A}$ | - | 6.5 | 8.6 | nC |
| Gate to drain charge | Q_{gd} | | - | 27 | 41 | |
| Gate charge total | Q_g | $V_{DD} = 80\text{V}$, $I_D = 35\text{A}$, $V_{GS} = 0$ to 10V | - | 49 | 65 | |
| Gate plateau voltage | $V_{(plateau)}$ | $V_{DD} = 80\text{V}$, $I_D = 35\text{A}$ | - | 6.1 | - | V |

Reverse Diode

| | | | | | | |
|--|----------|---|---|------|------|----|
| Inverse diode continuous forward current | I_S | $T_C = 25\text{ }^\circ\text{C}$ | - | - | 35 | A |
| Inverse diode direct current, pulsed | I_{SM} | | - | - | 140 | |
| Inverse diode forward voltage | V_{SD} | $V_{GS} = 0\text{V}$, $I_F = 35\text{A}$ | - | 0.95 | 1.25 | V |
| Reverse recovery time | t_{rr} | $V_R = 50\text{V}$, $I_F = I_S$, $di/dt = 100\text{A}/\mu\text{s}$ | - | 80 | 100 | ns |
| Reverse recovery charge | Q_{rr} | | - | 230 | 290 | nC |

1 Power dissipation

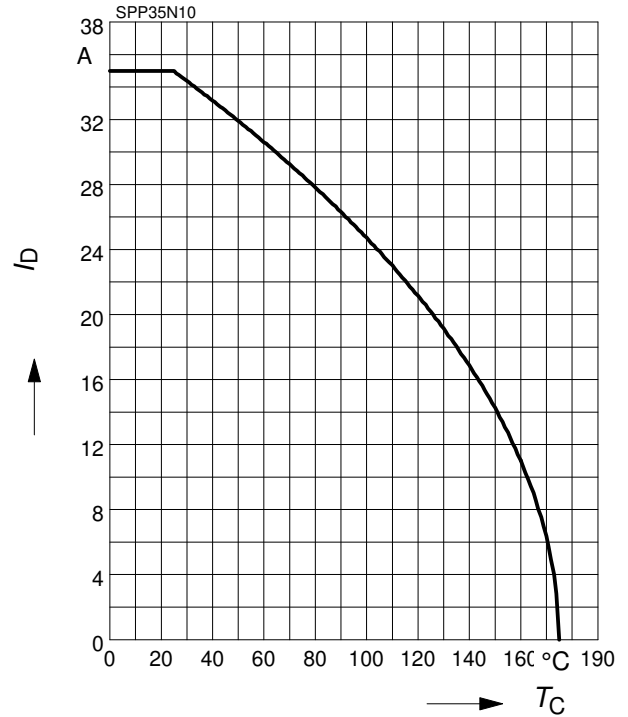
$$P_{tot} = f(T_C)$$



2 Drain current

$$I_D = f(T_C)$$

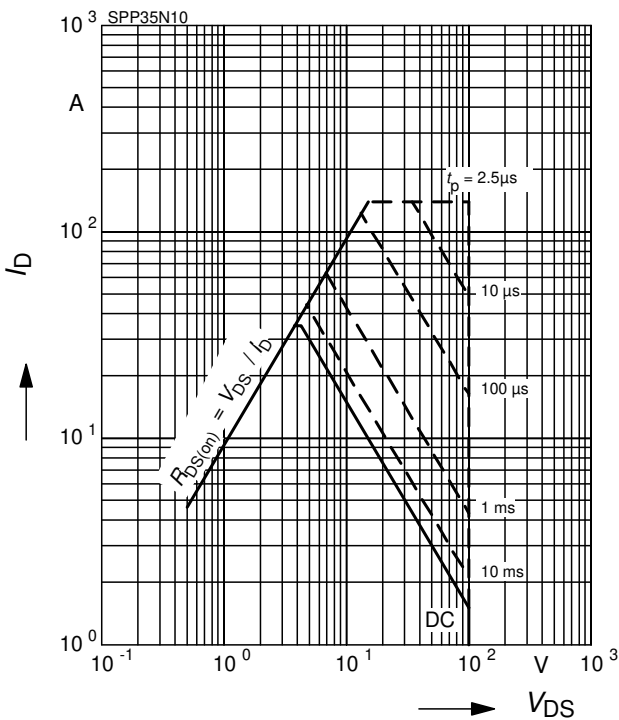
parameter: $V_{GS} \geq 10 \text{ V}$



3 Safe operating area

$$I_D = f(V_{DS})$$

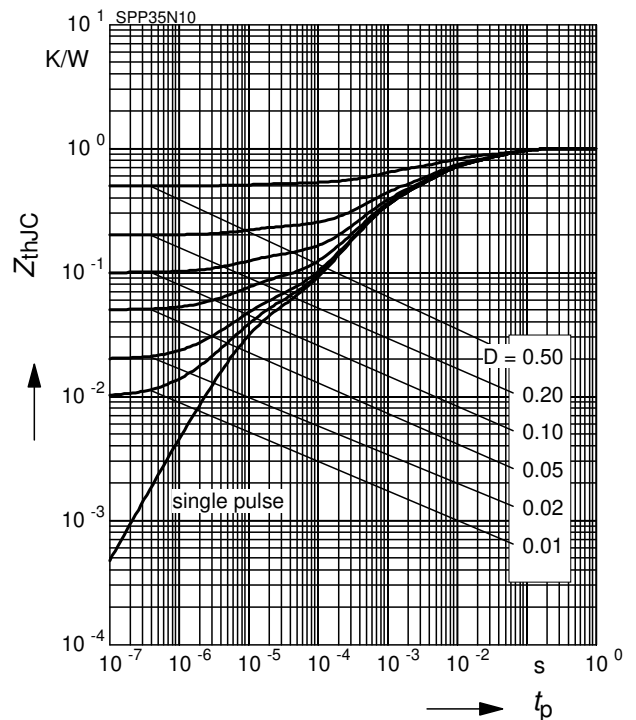
parameter: $D = 0$, $T_C = 25 \text{ °C}$



4 Transient thermal impedance

$$Z_{thJC} = f(t_p)$$

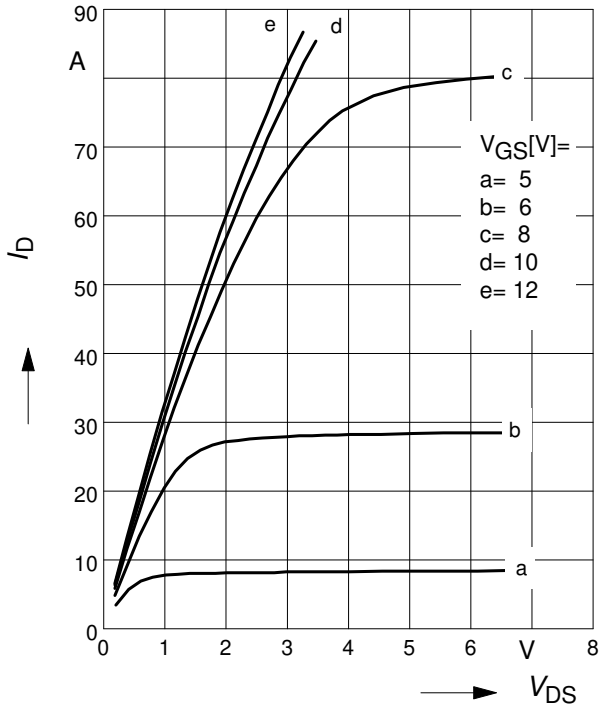
parameter: $D = t_p/T$



5 Typ. output characteristic

$$I_D = f(V_{DS}); T_j = 25^\circ\text{C}$$

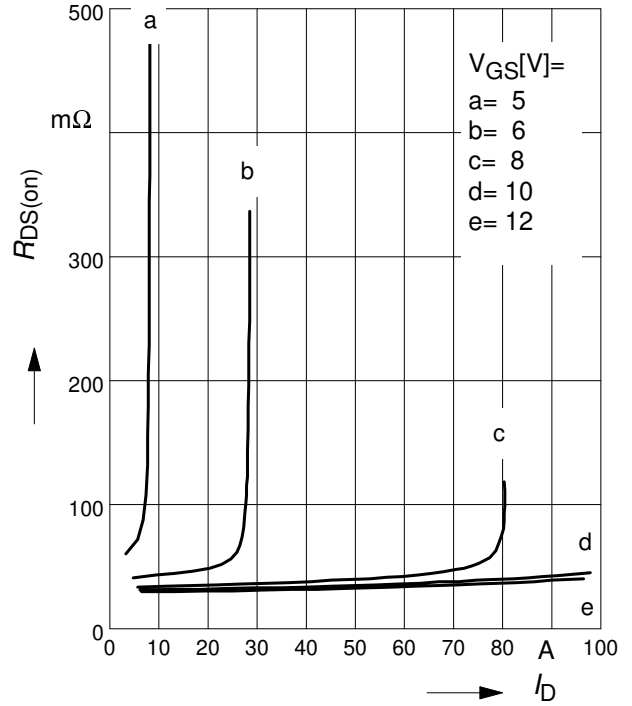
parameter: $t_p = 80 \mu\text{s}$



6 Typ. drain-source on resistance

$$R_{DS(on)} = f(I_D)$$

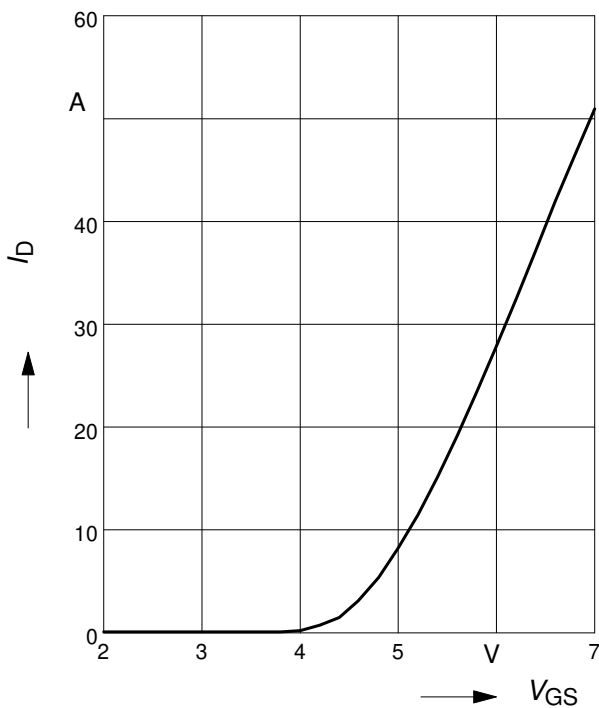
parameter: V_{GS}



7 Typ. transfer characteristics

$$I_D = f(V_{GS}); V_{DS} \geq 2 \times I_D \times R_{DS(on)max}$$

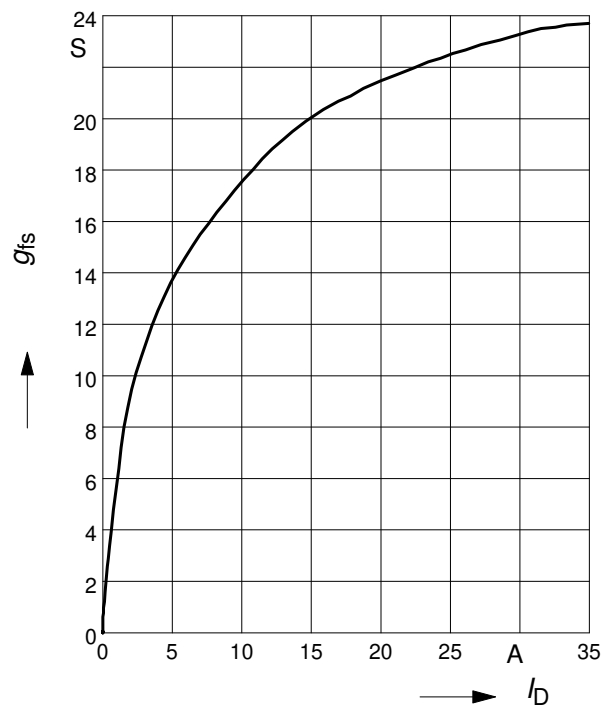
parameter: $t_p = 80 \mu\text{s}$



8 Typ. forward transconductance

$$g_{fs} = f(I_D); T_j = 25^\circ\text{C}$$

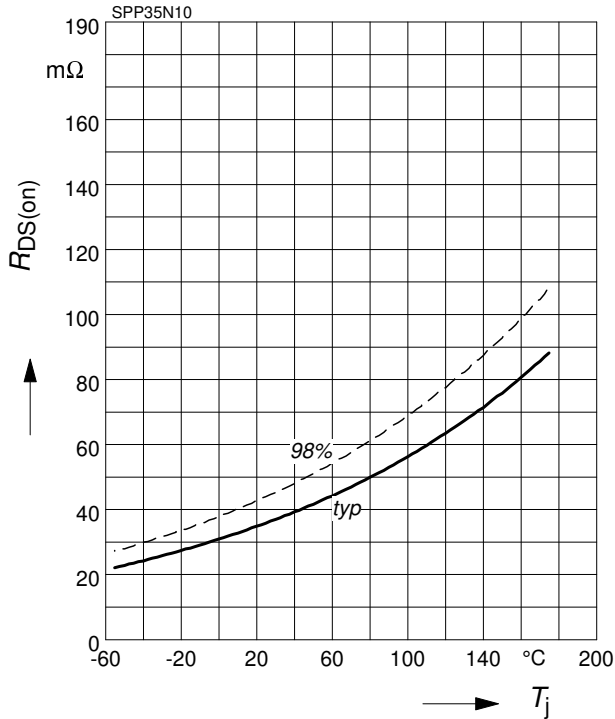
parameter: g_{fs}



9 Drain-source on-state resistance

$$R_{DS(on)} = f(T_j)$$

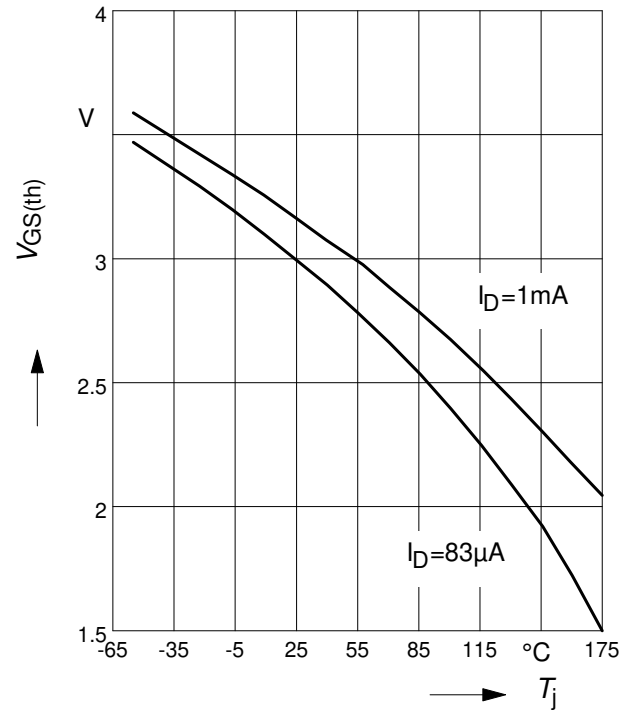
parameter: $I_D = 26.4 \text{ A}$, $V_{GS} = 10 \text{ V}$



10 Typ. gate threshold voltage

$$V_{GS(th)} = f(T_j)$$

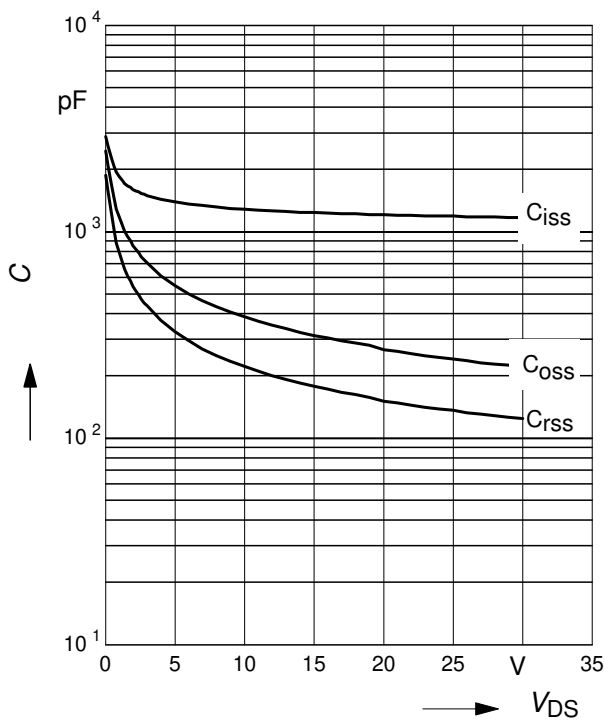
parameter: $V_{GS} = V_{DS}$



11 Typ. capacitances

$$C = f(V_{DS})$$

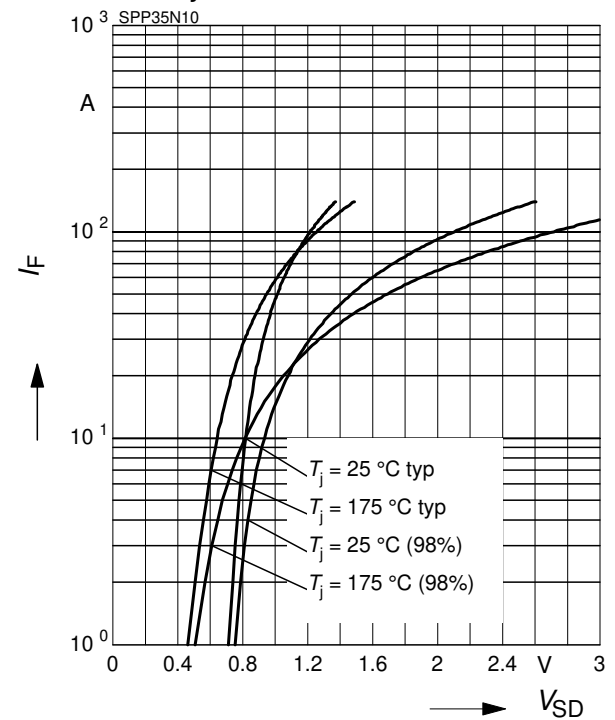
parameter: $V_{GS} = 0 \text{ V}$, $f = 1 \text{ MHz}$



12 Forward character. of reverse diode

$$I_F = f(V_{SD})$$

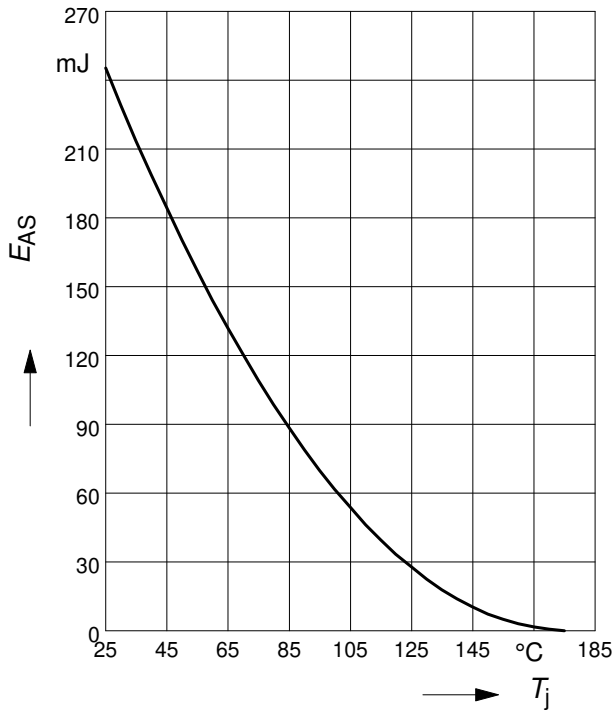
parameter: T_j , $t_p = 80 \mu\text{s}$



11 Typ. avalanche energy

$$E_{AS} = f(T_j)$$

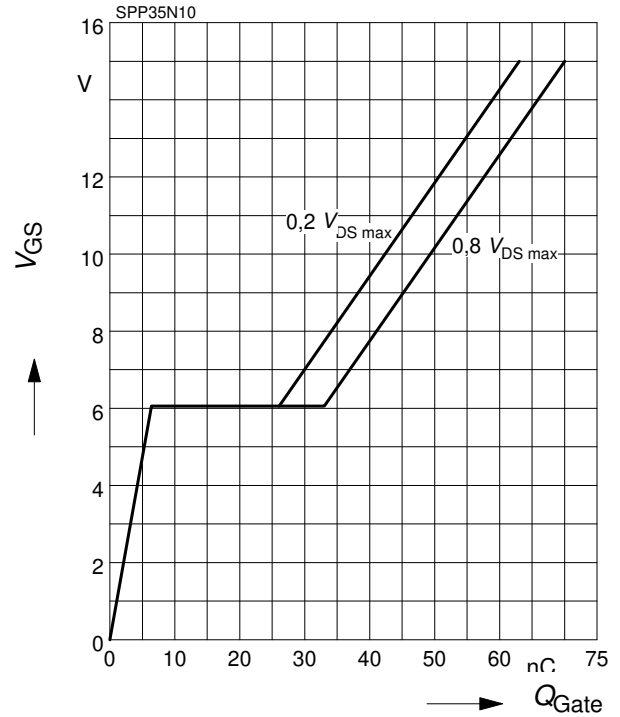
par.: $I_D = 35 \text{ A}$, $V_{DD} = 25 \text{ V}$, $R_{GS} = 25 \Omega$



12 Typ. gate charge

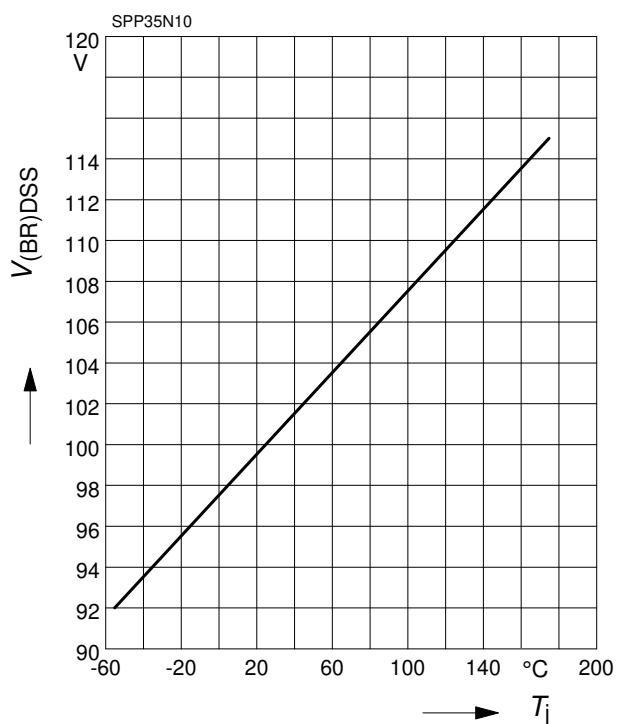
$$V_{GS} = f(Q_{Gate})$$

parameter: $I_D = 35 \text{ A}$ pulsed



13 Drain-source breakdown voltage

$$V_{(BR)DSS} = f(T_j)$$



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